

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Kazuki Yokota

Serial No.: 09/627,456

Group Art Unit: 2877

Filing Date: July 27, 2000

Examiner: Unknown

For: OVERLAY MARK, METHOD OF MEASURING OVERLAY ACCURACY,  
METHOD OF MAKING ALIGNMENT AND SEMICONDUCTOR DEVICE  
THEREWITH

Assistant Commissioner of Patents  
Washington, D.C. 20231

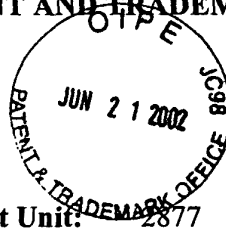
INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 CFR §1.97 through §1.99 and pursuant to applicant's duty of disclosure under 37 CFR §1.56, applicant respectfully brings the following documents cited in the Japanese Office Action and the Korean Office Action listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application. Copies of the listed documents are provided herewith for the convenience of the Examiner.

In compliance with the requirements of 37 CFR §1.98(a)(3), as a concise statement of relevance, as it is presently understood by the individual designated in 35 U.S.C. §1.56(c) most knowledgeable about the content of the information, the undersigned attorney of record submits a translation of portions of an official action by a foreign examiner in which the reference was cited. The relevance to the pending U.S. patent application is that the reference was cited in a foreign patent application on the same subject matter. However, no independent analysis of the reference, the accuracy of the statement of the foreign examiner or the claims of the foreign application under the laws of that country or the United States relative to the subject matter claimed in the present application has been made, the present understanding of the contents thereof by the undersigned being based on the translation of the foreign examiner's comments submitted herewith.

This citation does not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.



#7 IDS

M. Brunson  
6/26/02  
RECEIVED  
JUN 24 2002  
TECHNOLOGY CENTER 2000

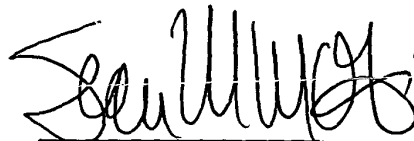
I hereby certify that each item of information contained in this Information Disclosure Statement was the first citation of that item by a foreign patent office in a counterpart foreign application, which occurred not more than three months prior to the filing of this statement.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully submitted,

Date: 6/21/02



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